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### Posters

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Number	Author	Title	
		<b>VUV and EUV instrumentation</b>	
1	E.F. Barte	<a href="#">Soft X-ray generation under the action of pico and nanosecond laser pulses on nano-structured target</a>	TU Prague
2	R. Lokasani	<a href="#">XUV emission from highly ionized plasmas of 2nd transition row elements, irradiated by Q-switched N</a>	TU Prague
3	J. van Veldhoven	<a href="#">Towards a contamination-tolerant EUV power sensor</a>	TNO
4	L. Rodriguez-de Marcos	<a href="#">VUV reflectometer for in-situ measurement of coatings</a>	CSIC
5	M. Tryus	<a href="#">A spatially resolving non-destructive tool for multi-angle EUV spectroscopic reflectometry</a>	RWTH
6	J. Bußmann	<a href="#">Coherent diffractive imaging for actinic inspection with EUV light produced by a laboratory-scale gas discharge radiation source</a>	RWTH
7	A. Sokolov	<a href="#">An XUV At-Wavelength Metrology facility at BESSY-II</a>	HZB
8	F. Nawaz	<a href="#">Capillary discharge based soft X-ray imaging setup, using Fresnel zone plate (FZP) optics</a>	TU Prague
9	D. Wilson	<a href="#">Laboratory-based photoemission spectro-microscopy at 71.7 eV for studies of complex materials</a>	FZJ
		<b>Optics &amp; Materials</b>	
10	P. Pennartz	<a href="#">Recent Developments for X-ray Optics, from EUV to hard X-Rays</a>	Rigaku
11	O. Hofmann	<a href="#">Investigation of Luminescent Materials for EUV Metrology Applications</a>	RWTH
12	A. Comisso	<a href="#">Optical Properties of TiO2 thin films from soft x-ray reflectivity measurements</a>	U Padova
13	F. Liu	<a href="#">EUV induced secondary electron emission on HfO2, SnO2, and Ru thin films</a>	MESA+
14	A. Zameshin	<a href="#">Free-form approach to reconstruct periodic multilayer structure from X-Ray reflectivity</a>	U Twente
15	E. Darlatt	<a href="#">Degradation of organic thin films by UV/VIS irradiation investigated by UPS and XPS</a>	PTB
16	T. Siefke	<a href="#">VUV wire grid polarizer based on interband absorption</a>	FSU
		<b>Detectors</b>	
17	A. Sorokin	<a href="#">Gas-monitor detectors for x-ray FELs</a>	DESY
18	V. Zbrodskii	<a href="#">SiPM for direct VUV registration</a>	loffe
19	V. Zbrodskii	<a href="#">VUV detector based on SiC</a>	loffe
		<b>Scatter techniques</b>	
20	S. Burger	<a href="#">FEM Maxwell solver for EUV and X-ray scattering applications</a>	JCMwave
21	H. Groß	<a href="#">Impact of different LER patterns on scattered light intensities</a>	PTB